Supporting information

Nanostructured ZnO/ZnFe₂O₄ Heterojunction for Visible Light Photoelectrochemical Oxidation of Water

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Experimental

ZnO nanorods were prepared as follows: Precursor solution was prepared by dissolving 3.78 g zinc nitrate $(Zn(NO_3)_2)$ and 2.8 g hexamethylenetetramine $(C_6H_{12}N_4)$ in 100 mL DI water. The substrates deposited with zinc oxide seed layer were put in a 100 mL bottle containing 80 mL precursor solutions. The reaction was conducted at 95 °C for 3 h. After growth, the substrates were washed with deionized water several times and allowed to dry in air. The ZnO nanorods arrays were obtained after annealing the sample at 350 °C for 1 h to remove the organic residue.

ZnO seed layer on FTO were grown as following method: 0.5g zinc acetate and 0.25g poly(vinyl alcohol) powders were dissolved into 3 mL deionized water, followed by a vigorous magnetic stirring for 1 h at 60 °C to get zinc oxide colloid. The as-prepared zinc oxide colloid solution was then spin-coated on the pretreated FTO glass substrates and the samples were then annealed at 500 °C for 1 h.

Synthesis of $ZnFe_2O_4$ nanoparticles and surface modification were conducted according to the method reported earlier. ^{1,2} Deposition solution was prepared by dissolving 2 mg $ZnFe_2O_4$ particles in 5 mL DI water.

The morphology and size of ZnO nanorods and ZnO/ZnFe₂O₄ film were characterized by using a field-emission scanning electron microscope (Zeiss ULTRA Plus) operated at an accelerating voltage of 5 kV. X-ray diffraction patterns (XRD) were recorded on a PANalytical X'Pert PRO instrument using Cu K α radiation (40 kV, $\lambda = 1.5406$ Å) between 20° to 70° at a scanning rate of 0.067°/s. UV-visible diffusion reflectance spectra were measured on a UV-2550 (Shimadzu) spectrometer by using BaSO₄ as the reference. Photoelectrochemical measurements were made using a three-electrode configuration with the ZnO or ZnO/ZnFe₂O₄ film as the working photoelectrode, saturated calomel electrode (SCE) as the reference electrode, and platinum foil as the counter electrode in 0.1 M Na₂SO₄. Sunlight was simulated with a 300 W xenon lamp and an AM1.5G filter (HSX-F300, Beijing NBeT Technology Co., Ltd), coupled with a 420 nm UV filter. The light intensity was set using a calibrated crystalline silicon solar cell. Photocurrent response and electrochemical impedance spectroscopy (EIS) were recorded using a CHI-660D potentiostat. The superimposed alternating current (AC) signal was maintained at 5 mV, while the frequency was scanned between 100 kHz and 0.05 Hz at potentials of 0.8 V versus SCE under illumination by visible light in an electrolyte of 0.1 M Na₂SO₄, with Pt as the counter electrode. STEM-EDX mapping techniques were measured using an FEI Tecnai TF20 microscope operated at 200 kV.

References:

- 1. C.W. Yao, Q.S. Zeng, G. F. Goya, T. Torres, J.F. Liu, H.P. Wu, M.Y. Ge, Y.W. Zeng, Y.W. Wang and J.Z. Jiang, *J. Phys. Chem. C* 2007, *111*, 12274–12278.
- 2. Z.C. Liu, B. Li, B.D. Wang, Z.Y. Yang, Q. Wang, T.R. Li, D.D. Qin, Y. Li, M.F. Wang, M.H. Yan, *Dalton Trans.*, **2012**, *41*, 8723–8728.